

**Search Notes**

Application/Control No.

10/027,163

Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

COUTS ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
709	204	8/25/2005	DB
709	206	8/25/2005	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	8/25/2005	DB